



ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

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Title of Invention	SYSTEMS AND METHODS FOR INSPECTION OF SPECIMEN SURFACES																																																																																								
<p>Application Number: 09/965408</p> <p>Confirmation Number: 3796</p> <p>First Named Applicant: Eliezer Rosengaus</p> <p>Attorney Docket Number: 5589-02701</p> <p>Art Unit: 2877</p> <p>Examiner: Richard A. Rosenberger</p> <p>Search string: (5917588 or 6020957 or 5096291 or 4391524 or 4441124 or 4614427 or 4889998 or 5317380 or 5187596 or 4247203 or 4347001 or 4378159 or 4448532 or 4532650 or 4555798 or 4556317 or 4579455 or 4601576 or 4618938 or 4633504 or 4641967 or 4644172 or 4766324 or 4805123 or 4818110 or 4845558 or 4877326 or 4898471 or 4926489 or 5076692 or 5189481 or 5264912 or 5355212 or 5537669 or 5563702 or 5565979 or 5572598 or 5604585 or 5737072 or 5798829 or 5822055 or 5864394 or 5883710 or 6020214 or 6052478 or 6064517 or 6078386 or</p>																																																																																									
<h3>US Patent Documents</h3> <p>Note: Applicant is not required to submit a paper copy of cited US Patent Documents</p> <table border="1"><thead><tr><th>init</th><th>Cite.No.</th><th>Patent No.</th><th>Date</th><th>Patentee</th><th>Kind</th><th>Class</th><th>Subclass</th></tr></thead><tbody><tr><td></td><td>1</td><td>5917588</td><td>1999-06-29</td><td>Addiego</td><td></td><td></td><td></td></tr><tr><td></td><td>2</td><td>6020957</td><td>2000-02-01</td><td>Rosengaus et al.</td><td></td><td></td><td></td></tr><tr><td></td><td>3</td><td>5096291</td><td>1992-03-17</td><td>Scott</td><td></td><td></td><td></td></tr><tr><td></td><td>4</td><td>4391524</td><td>1983-07-05</td><td>Steigmeier et al.</td><td></td><td></td><td></td></tr><tr><td></td><td>5</td><td>4441124</td><td>1984-04-03</td><td>Heebner et al.</td><td></td><td></td><td></td></tr><tr><td></td><td>6</td><td>4614427</td><td>1986-09-30</td><td>Koizumi et al.</td><td></td><td></td><td></td></tr><tr><td></td><td>7</td><td>4889998</td><td>1989-12-26</td><td>Hayano et al.</td><td></td><td></td><td></td></tr><tr><td></td><td>8</td><td>5317380</td><td>1994-05-31</td><td>Allemand</td><td></td><td></td><td></td></tr><tr><td></td><td>9</td><td>5187596</td><td>1993-02-16</td><td>Hwang</td><td></td><td></td><td></td></tr><tr><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td></tr></tbody></table>		init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass		1	5917588	1999-06-29	Addiego					2	6020957	2000-02-01	Rosengaus et al.					3	5096291	1992-03-17	Scott					4	4391524	1983-07-05	Steigmeier et al.					5	4441124	1984-04-03	Heebner et al.					6	4614427	1986-09-30	Koizumi et al.					7	4889998	1989-12-26	Hayano et al.					8	5317380	1994-05-31	Allemand					9	5187596	1993-02-16	Hwang											
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Signature

Examiner Name	Date
Richard A. [Signature]	6/25/04

Form PTO-1449 (modified) List of Patents and Publications For Applicant's Information Disclosure Statement (Use several sheets if necessary)	ATTY. DKT. NO. 5589-02701	SERIAL NO. 09/965,408
	APPLICANT: Rosengaus et al.	GROUP: 2877
	FILING DATE: September 25, 2001	

U.S. PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>m</i>	A1	5,815,607	9/29/1998	Miura			

FOREIGN PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>m</i>	A2	Patent Abstracts of Japan, publication no. 62276443, published December 1, 1987.					
<i>m</i>	A3	Patent Abstracts of Japan, publication no. 04332854, published November 19, 1992.					
<i>m</i>	A4	Kitamura et al., "Automatic Macro Inspection System," SPIE Vol. 3998, 2000, pp. 615-621.					
<i>m</i>	A5	"Contact image sensor heads," © ROHM Co., Ltd., 5 pages.					
<i>m</i>	A6	International Search Report, application no. PCT/US 02/02555, mailed February 5, 2003.					

EXAMINER:

DATE CONSIDERED:

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Information Disclosure Statement--PTO 1449 (modified)